Sandip Institute of Technology and Research Centre
At & Po – Mahirawani, Trimbak Road, Tal & Dist. – Nashik
Phone: (02594) 222552,53,54, Fax: (02594) 222555
website : www.sandipfoundation.org, e-mail : principal@sitrc.org
(Approved by-AICTE, New Delhi, & Govt. of Maharashtra and Permanently Affiliated to Savitribai Phule Pune University (Formerly Pune University), Pune.
Accredited with "A" grade by NAAC With CGPA Score of 3.11

DEPARTMENT OF ELECTRICAL ENGINEERING

(A.Y 2024-25)

NOTICE

Date:- 01/8/2024

All students of SE are hereby inform that the Department of Electrical Engineering is going to conduct free of cost VAP on **"Testing of Electrical Components"** on date 26/8/2024 to 30/8/2024 for SE student's.

Interested students enroll their name to Prof. R. M. Patil before **23/08/2024.**

Resource Person: Prof. R. B. Sadaphale, EE Dept, SITRC, Nashik

Time: 10:00AM To 5.00PM

Venue: EE Dept .SITRC, Nashik

Dr. N. S. Patil
HOD
Electrical Engineering

Dr. Amol D. Potgantwar
Principal
SITRC, Nashik

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DEPARTMENT OF ELECTRICAL ENGINEERING

(A.Y 2024-25)

Theory Course Content- Topics covered during the Value Added Program-

Module 1: Introduction to Testing and Testing Methodologies

Module 2: Testing of Passive Components

Module 3: Testing of Active Components

Module 4: Testing of Electro-mechanical Components

Module 5: Advanced Testing Techniques and Troubleshooting

Program Agenda-

Day	Time	Program	Topic
1	10 am To 1 pm	Morning session	Module 1: Introduction to Testing and Testing Methodologies
	1 pm To 2 pm	**Lunch Break**	
	2 pm To 5 pm	Evening Session	Module 1: Introduction to Testing and Testing Methodologies
2	10 am To 1pm	Morning session	Module 2 : Testing of Passive Components
	1 pm To 2 pm	**Lunch Break**	
	2pm To 5 pm	Evening Session	Module 2: Testing of Passive Components
3	10 am To 1pm	Morning session	Module 3: Testing of Active Components
	1 pm To 2 pm	**Lunch Break**	
	2pm To 5 pm	Evening Session	Module 3: Testing of Active Components
4	10 am To 1pm	Morning session	Module 4: Testing of Electro-mechanical Components
	1 pm To 2 pm	**Lunch Break**	
	2pm To 5 pm	Evening Session	Module 4: Testing of Electro-mechanical Components
5	10 am To 1pm	Morning session	Module 5: Advanced Testing Techniques and Troubleshooting
	1 pm To 2 pm	**Lunch Break**	
	2pm To 5 pm	Evening Session	Module 5: Advanced Testing Techniques and Troubleshooting

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DEPARTMENT OF ELECTRICAL ENGINEERING

(A.Y 2024-25)

VAP Report

Name of the Event: VAP on **"Testing of Electrical Components"**

Event Date: 26/8/2024 to 30/8/2024

Event Conduction Duration: 10.00 am to 5.00 pm

No of Participants: SE: 75 Students

Name of Resource Person: Prof. R. B. Sadaphale, EE Dept, SITRC, Nashik

Name of Event Coordinator: Prof. R. M. Patil (Asst. Prof, Electrical Dept., SITRC, Nashik)

The **Value Added Program (VAP) on Testing of Electrical Components** is designed to provide participants with a comprehensive understanding of the testing processes and techniques used in the electronics and electrical engineering industry. This program focuses on the testing of various components, including passive components (resistors, capacitors, inductors), active components (diodes, transistors, operational amplifiers), and electro-mechanical components (relays, motors, switches).

Course Objectives:

1. **Introduction to Component Testing**: To familiarize participants with the importance of component testing in ensuring quality and reliability in electronics and electrical engineering.
2. **Testing Techniques and Equipment**: To provide hands-on experience in using various testing instruments such as multimeters, oscilloscopes, LCR meters, and automated testing systems for component testing.
3. **Testing Passive Components**: To develop proficiency in testing passive components (resistors, capacitors, inductors), including methods for identifying faults and performance issues.

4. **Testing Active Components**: To impart knowledge on testing active components such as diodes, transistors, and operational amplifiers, including the identification of common faults and degradation.
5. **Electro-mechanical Component Testing**: To introduce participants to the testing and troubleshooting of electro-mechanical components, such as relays, motors, and switches, and help them develop diagnostic skills.

Course Outcomes:

1. **Proficiently Use Test Equipment**: Participants will be able to use various testing tools such as multimeters, oscilloscopes, LCR meters, and function generators to test components effectively.
2. **Test Passive Components**: Successfully test passive components (resistors, capacitors, inductors), check their functionality, and identify faults using standard testing methods.
3. **Test Active Components**: Effectively test active components like diodes, transistors, and op-amps, and diagnose common faults related to these components.
4. **Test Electro-mechanical Components**: Understand how to test and troubleshoot electro-mechanical components such as motors, relays, and switches, ensuring they operate efficiently.
5. **Implement Troubleshooting Techniques**: Develop systematic troubleshooting skills for diagnosing and fixing faulty components using test equipment and manual inspection techniques.
6. **Perform Advanced Testing Techniques**: Apply advanced testing methodologies and use automated testing systems to improve testing accuracy and efficiency in complex electronic systems.
7. **Work on Real-World Testing Scenarios**: Gain hands-on experience through practical exercises and projects that simulate real-world testing and troubleshooting situations.

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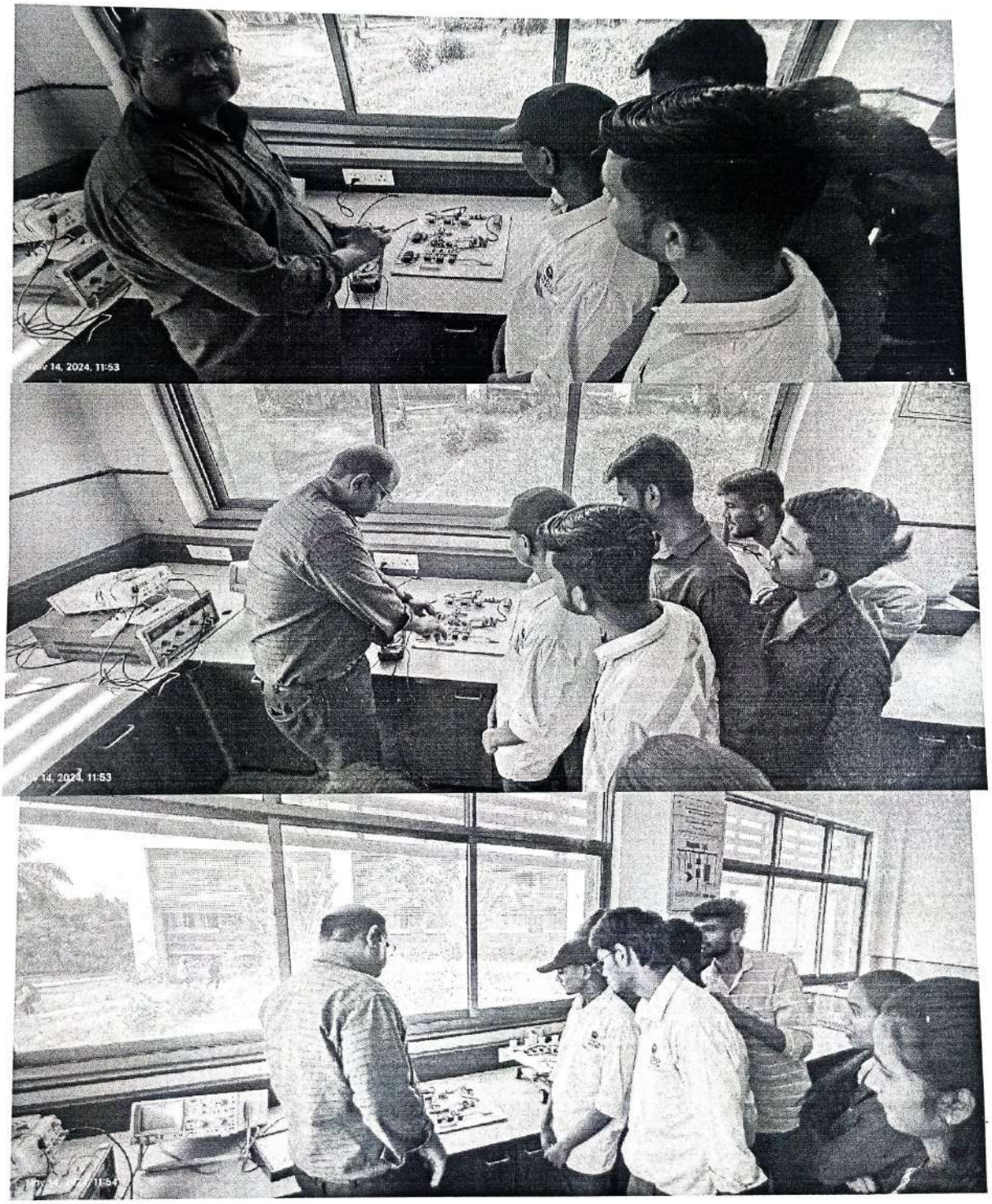
EVENT PHOTOS:



Prof. R. B Sadaphale explaining about the Testing of Electrical Component